MITSUBISHI ELECTRIC

<Full SiC Power Modules>

FMF300E3XZ-34B

HIGH POWER SWITCHING USE
INSULATED TYPE

Chopper

Drain current I_D ..... **300** A

Drain-Source voltage V_{DSX} ..... **1700** V

Maximum junction temperature T_{vjmax} ..... **175** °C

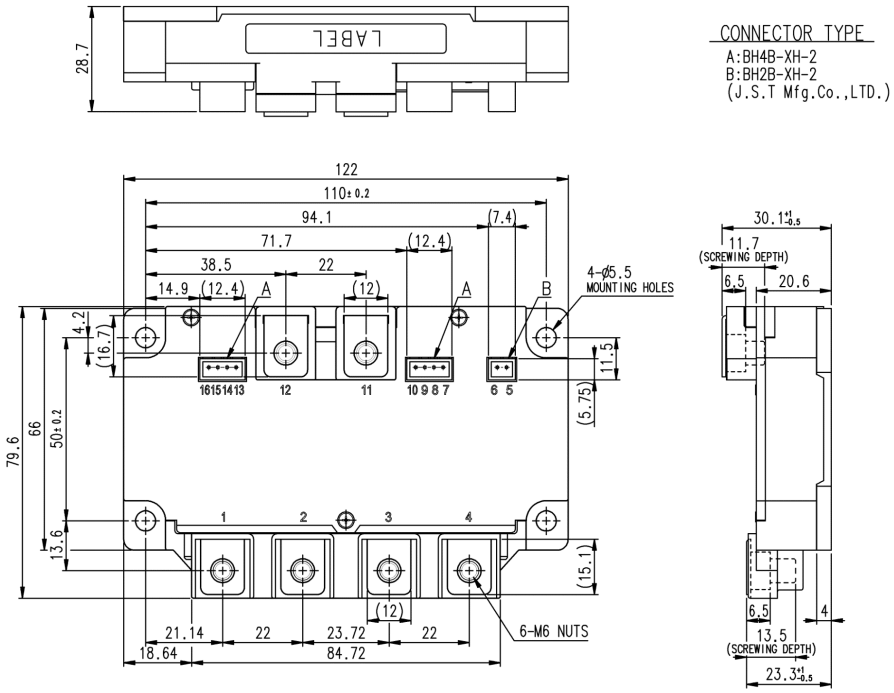
- Silicon Carbide MOSFET + Silicon Carbide Schottky Barrier Diode
- Flat base Type
- Copper base plate
- RoHS Directive compliant
- Recognized under UL1557, File E323585

APPLICATION

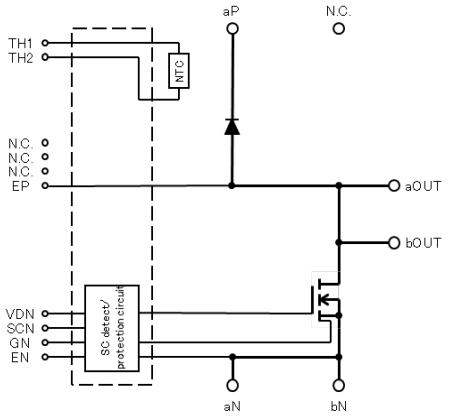
Power supply

OUTLINE DRAWING & INTERNAL CONNECTION

Dimension in mm



INTERNAL CONNECTION



Terminal	code
1	aP
2	aN
3	bN
4	N.C.
5	TH1
6	TH2
7	VDN
8	SCN
9	GN
10	EN
11	bOUT
12	aOUT
13	EP
14	N.C.
15	N.C.
16	N.C.

Tolerance otherwise specified

Division of Dimension		Tolerance
0.5	to 3	±0.2
over 3	to 6	±0.3
over 6	to 30	±0.5
over 30	to 120	±0.8
over 120	to 400	±1.2

aN and bN, aOUT-bOUT must be connected externally.

MAXIMUM RATINGS (T_{vj} =25 °C, unless otherwise specified)

MOSFET

Symbol	Item	Conditions	Rating	Unit
V_{DSX}	Drain-source voltage	V_{GS}=-15 V	1700	V
V_{GSS}	Gate-source voltage	D-S short-circuited	±20	V
I_D	Drain current	DC, T_C=48℃ (Note.1)	300	A
I_{DRM}		Pulse, Repetitive (Note.2), T_{vj}=150℃	450	
P_{tot}	Total power dissipation	T_C=25 °C (Note. 1)	1230	W

SBD

Symbol	Item	Conditions	Rating	Unit
V_{RRM}	Repetitive peak reverse voltage	-	1700	V
I_F	Forward current	DC	300	A
I_{FRM}		Pulse, Repetitive (Note.2)	450	

MODULE

Symbol	Item	Conditions	Rating	Unit
V_{isol}	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	5000	V
T_{vjmax}	Maximum junction temperature	Instantaneous event (overload) (Note.9)	175	°C
T_{vjop}	Operating junction temperature	Continuous operation (under switching) (Note.9)	-40～+150	°C
T_{cmax}	Maximum case temperature	(Note.1, 9)	125	°C
T_{stg}	Storage temperature	-	-40～+125	°C

ELECTRICAL CHARACTERISTICS (T_{vj}=25 °C, unless otherwise specified)]

MOSFET

Symbol	Item	Conditions (note.8)		Limits			Unit
				Min.	Typ.	Max.	
I_{DSX}	Drain-source cut-off current	V_{DS}=V_{DSX}, V_{GS}=-15 V		-	-	0.1	mA
$V_{GS(th)}$	Gate-source threshold voltage	I_D=113 mA, V_{DS}=10 V		1.8	2.5	3.2	V
I_{GSS}	Gate-source leakage current	V_{GS}=V_{GSS}, D-S short-circuited		-	-	0.5	μA
$V_{DS(on)}$ (terminal)	Drain-source on-state voltage	I_D=300 A, V_{GS}=15V (Note.5)	T_{vj}=25 °C	-	1.65	2.60	V
			T_{vj}=125 °C	-	2.19	-	
			T_{vj}=150 °C	-	2.33	-	
$V_{DS(on)}$ (chip)	Drain-source on-state voltage	I_D=300 A, V_{GS}=15V (Note.5)	T_{vj}=25 °C	-	1.47	-	V
			T_{vj}=125 °C	-	2.01	-	
			T_{vj}=150 °C	-	2.15	-	
$r_{DS(on)}$ (chip)	Drain-source on-state resistance	I_D=300 A, V_{GS}=15V (Note.5)	T_{vj}=25 °C	-	4.90	-	mΩ
			T_{vj}=125 °C	-	6.70	-	
			T_{vj}=150 °C	-	7.16	-	
C_{iss}	Input capacitance	V_{DS}=10 V, V_{GS}=0V		-	27.4	-	nF
C_{oss}	Output capacitance			-	11.5	-	
C_{rss}	Reverse transfer capacitance			-	0.98	-	
Q_G	Gate charge	V_{DD}=900 V, I_D=300 A, V_{GS}=0→15 V		-	800	-	nC
$t_{d(on)}$	Turn-on delay time	V_{DD}=900 V, I_D=300 A, V_{GS}=±15 V, T_{vj}=150℃, R_G=1.5Ω, L_{s_ext}=16nH, Inductive load, per pulse		-	200	-	ns
t_r	Rise time			-	50	-	
$t_{d(off)}$	Turn-off delay time			-	220	-	
t_f	Fall time			-	30	-	
E_{on}	Turn-on switching energy			-	16	-	mJ
E_{off}	Turn-off switching energy			-	5	-	
Q_C	Drain-source charge			-	2	-	μC
r_g	Internal gate resistance	Per switch		-	0.5	-	Ω

SBD

Symbol	Item	Conditions (note.8)		Limits			Unit
				Min.	Typ.	Max.	
I_{RRM}	Reverse current	V_{RM}=V_{RRM}		-	-	5	mA
		V_{DS}=1000V, V_{GS}=-15 V		-	-	0.5	
V_F (terminal)	Forward voltage	I_F=300 A(Note.5)	T_{vj}=25 °C	-	1.80	2.40	V
			T_{vj}=125 °C	-	2.45	-	
			T_{vj}=150 °C	-	2.69	-	
V_F (chip)	Forward voltage	I_F=300 A (Note.5)	T_{vj}=25 °C	-	1.64	-	V
			T_{vj}=125 °C	-	2.28	-	
			T_{vj}=150 °C	-	2.52	-	

MODULE

Symbol	Item	Conditions (note.8)	Limits			Unit
			Min.	Typ.	Max.	
$R_{DD'+SS'}$	Internal lead resistance	P-N	-	0.6	-	mΩ
L_s	Internal stray inductance	P-N	-	25	-	nH

THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
$R_{th(j-c)Q}$	Thermal resistance(Note. 1)	Junction to case, per inverter switch	-	-	121	K/kW
$R_{th(j-c)D}$		Junction to case, per inverter FWD	-	-	131	
$R_{th(c-s)}$	Contact thermal resistance(Note.1)	Case to heat sink, per 1 module, Thermal grease applied (Note.7, 9)	-	12	-	K/kW

NTC THERMISTOR PART

Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
R_{25}	Zero-power resistance	T_C=25 °C (Note.1)	4.85	5.00	5.15	kΩ
ΔR/R	Deviation of resistance	T_C=100 °C (Note.1) ,R_{100}=493 Ω	-7.3	-	+7.8	%
$B_{(25/50)}$	B-constant	Approximate by equation (Note.6)	-	3375	-	K
P_{25}	Power dissipation	T_C=25 °C (Note.1)	-	-	10	mW

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
M_t	Mounting torque	Main terminals M 6 screw	3.5	4.0	4.5	N·m
M_s		Mounting to heat sink M 5 screw	2.5	3.0	6.0	
m	mass	-	-	500	-	g
d_a	Clearance		10	-	-	mm
d_s	Creepage distance		17	-	-	mm
e_c	Flatness of base plate	On the centerline X, Y (Note.4)	-100	-	+100	μm
-	Connector insertion force	2 pin type	0	-	25	N
		4 pin type	0	-	35	N

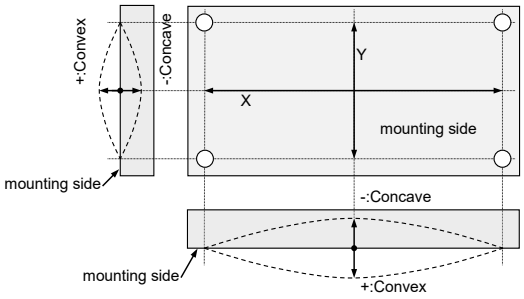
*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU and (EU)2015/863.

Note1. Case temperature (T_C) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

2. Pulse width and repetition rate should be such that the device junction temperature (T_{vj}) does not exceed T_{vjmax} rating.

3. Junction temperature (T_{vj}) should not increase beyond T_{vjmax} rating.

4. The base plate (mounting side) flatness measurement points (X, Y) are as follows of the following figure.



5. Pulse width and repetition rate should be such as to cause negligible temperature rise.

6. $B_{(25/50)} = \ln(\frac{R_{25}}{R_{50}}) / (\frac{1}{T_{25}} - \frac{1}{T_{50}})$

R_{25}: resistance at absolute temperature T_{25} [K]; T_{25}=25 [°C]+273.15=298.15 [K]
R_{50}: resistance at absolute temperature T_{50} [K]; T_{50}=50 [°C]+273.15=323.15 [K]

7. Typical value is measured by using thermally conductive grease of λ=0.9 W/(m·K)/$D_{(C-S)}$=100μm.

8. Per switch (ex. Tr1 chips total in page.7)

9. Long term performance related to thermal conductive grease (including but not limited to aspects such as the increase of thermal resistance due to pumping out, etc.) should be verified under your specific application conditions. Each temperature condition ($T_{vj\,max}$, $T_{vj\,op}$, $T_{C\,max}$) must be maintained below the maximum rated temperature throughout consideration of the temperature rise even for long term usage.

RECOMMENDED OPERATING CONDITIONS

Symbol	Item	Conditions		Limits			Unit
				Min.	Typ.	Max.	
V_{DD}	(DC) Supply voltage	Applied across aP -aN+bN terminals		-	900	1200	V
V_D	DC supply voltage (control)	Applied across VDN-EN terminals		13.5	15.0	16.5	V
$V_{GS(+)}$	Gate-Source positive drive voltage	Applied across GN-EN terminals		13.5	15.0	16.5	V
$V_{GS(-)}$	Gate-Source negative drive voltage	Applied across GN-EN terminals		-16.5	-15.0	-7.0	V
R_G	External gate resistance (Note.10)	Per switch		1.5	-	7.5	Ω
f_c	Switching frequency	$V_{GS(+)}$=15V, R_G=1.5Ω, V_{DD}=900V, T_{vj}=150℃	$V_{GS(-)}$＜-10V	-	-	50	kHz
			$V_{GS(-)}$≧-10V	-	-	100	kHz
$t_{d(SCoff)}$	Gate cutoff delay time after SC output	V_{GS}=15V, R_G=1.5Ω, V_{DD}≦1200V, T_{vj}=150℃		-	-	3	μs

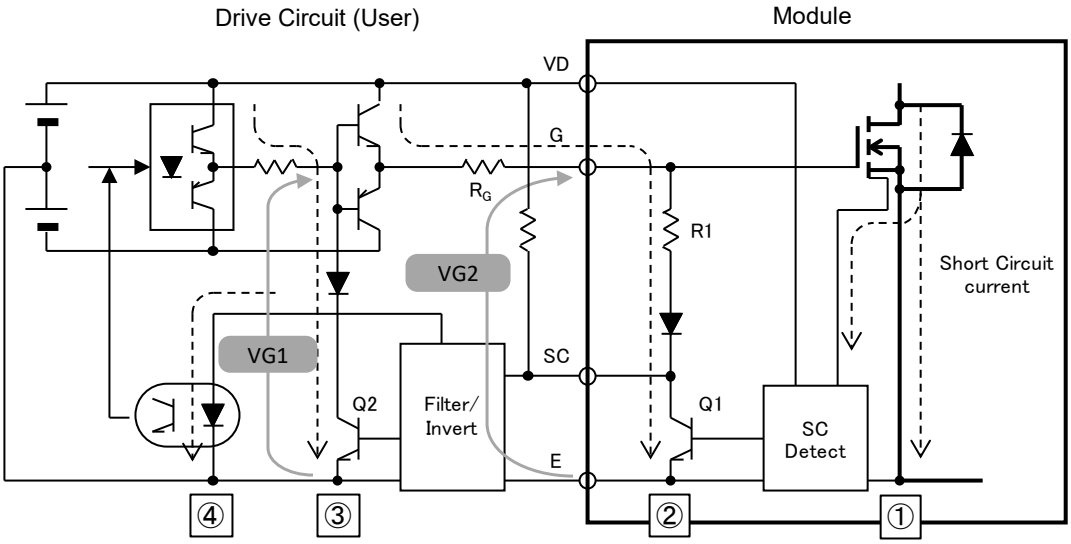
Note 10. The value of external gate resistance should be considered the surge voltage not to exceed the rating voltage in the worst system condition.

SHORT CIRCUIT DETECTION & PROTECTION CHARACTERISTICS

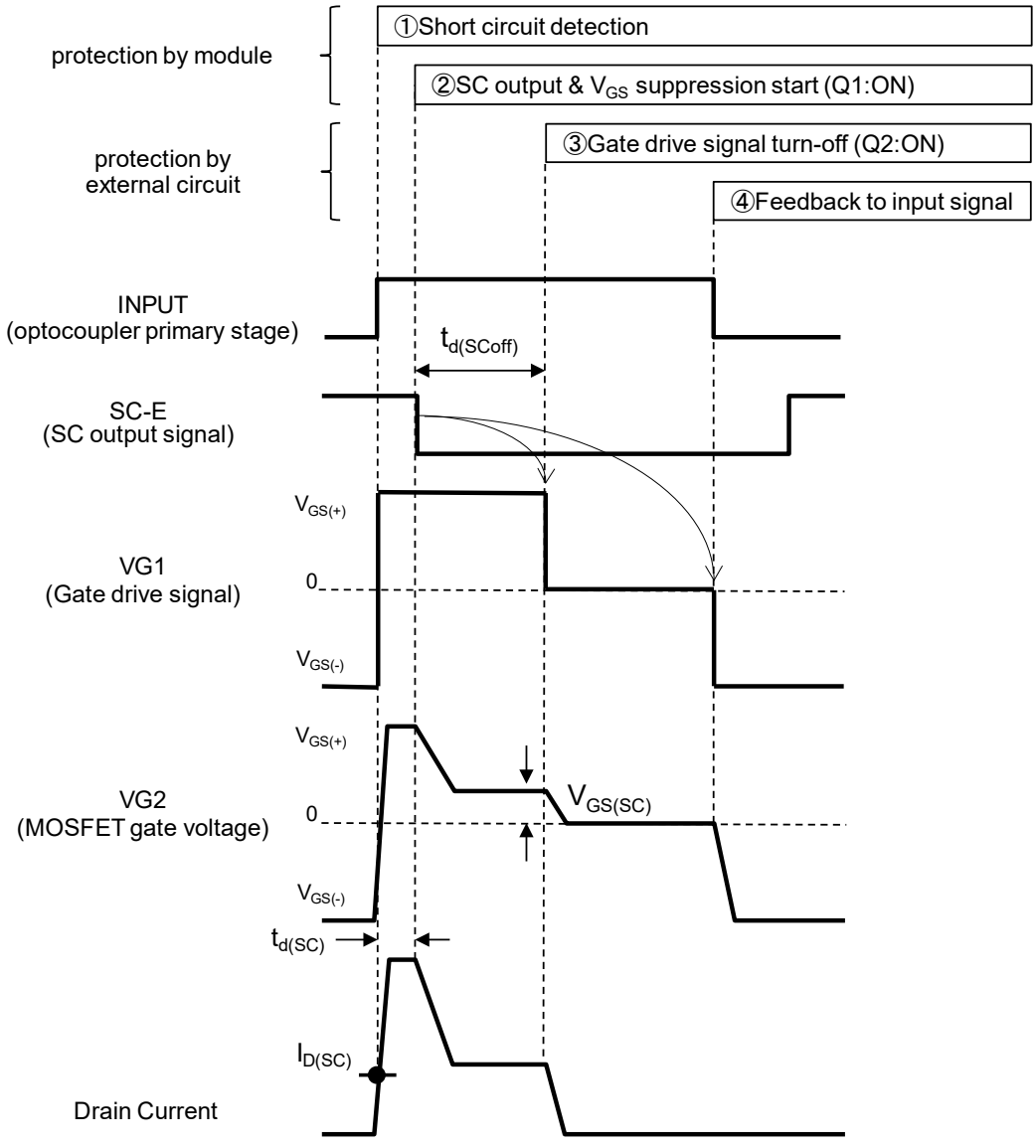
Symbol	Item	Conditions	Limits			Unit
			Min.	Typ.	Max.	
$I_{D(SC)}$	SC detect drain current	T_{vj}=150℃, V_{GS}=15V	450	600	-	A
$t_{d(SC)}$	SC detect delay time	T_{vj}=150℃, V_{DD}≦1200V, V_{GS}=15V, R_G=1.5Ω	-	1	-	μs
$V_{GS(SC)}$	SC protection gate limit voltage	T_{vj}=150℃, V_{GS}=15V, R_G=1.5Ω	-	0	-	V
R1	SC protection gate limit resistance	-	-	0	-	Ω

Refer to the circuit in page.6

SHORT CIRCUIT DETECTION & PROTECTION



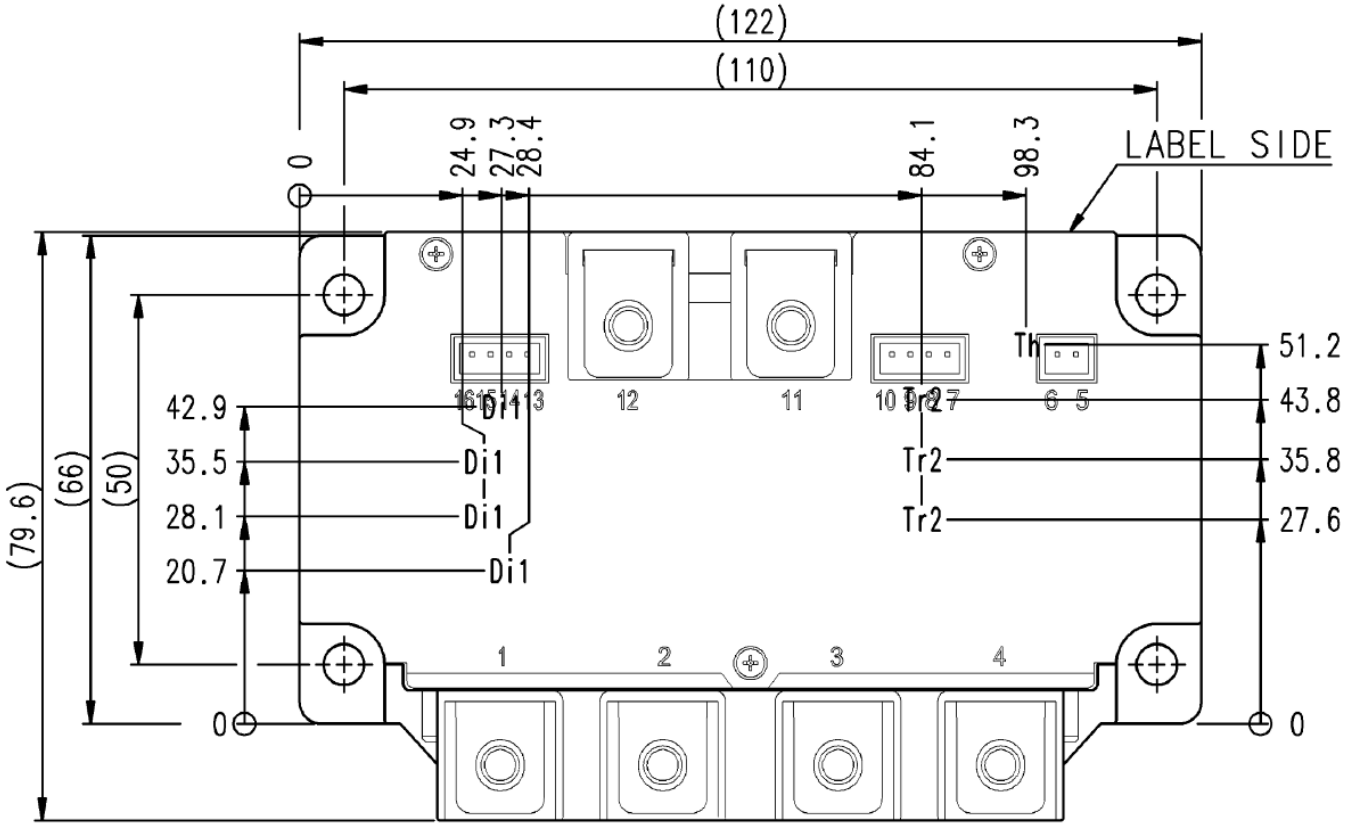
Example of application (Short circuit detection & protection)



Short circuit detection & protection diagram

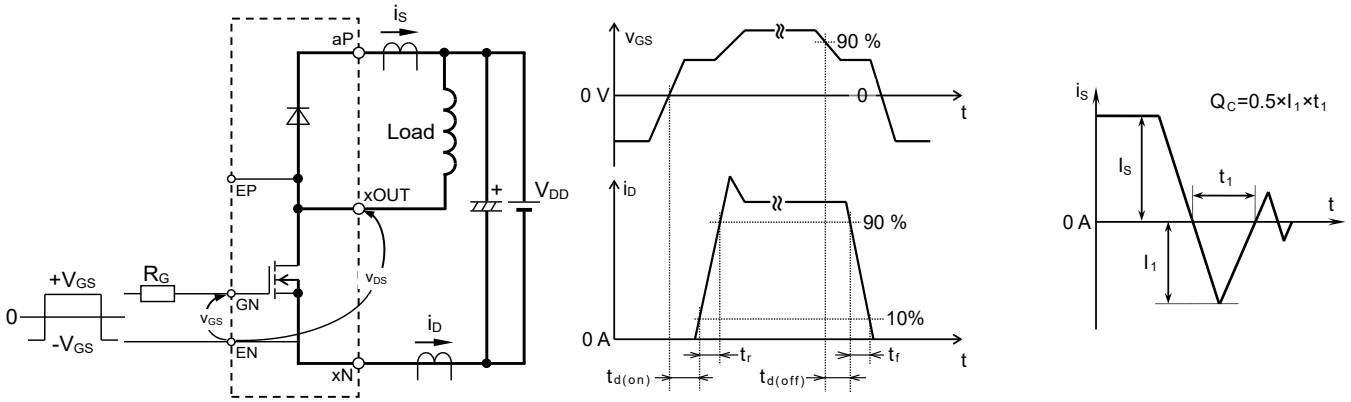
CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm



Tr2: SiC-MOSFET, Di1: SiC-SBD, Th: NTC thermistor

TEST CIRCUIT AND WAVEFORMS



Switching characteristics test circuit and waveforms(x: connected a* and b*)

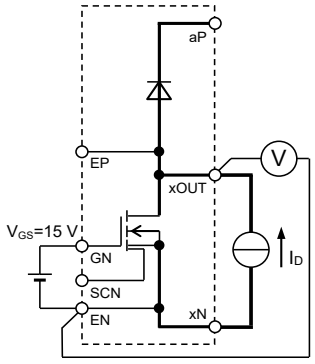
Q_C test waveform

MOSFET Turn-on switching energy

MOSFET Turn-off switching energy

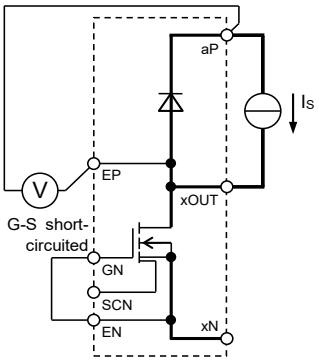
Turn-on / Turn-off switching energy test waveforms (Integral time instruction drawing)

TEST CIRCUIT



Tr2

$V_{DS(on)}$ test circuit (x: Connected a* and b*)

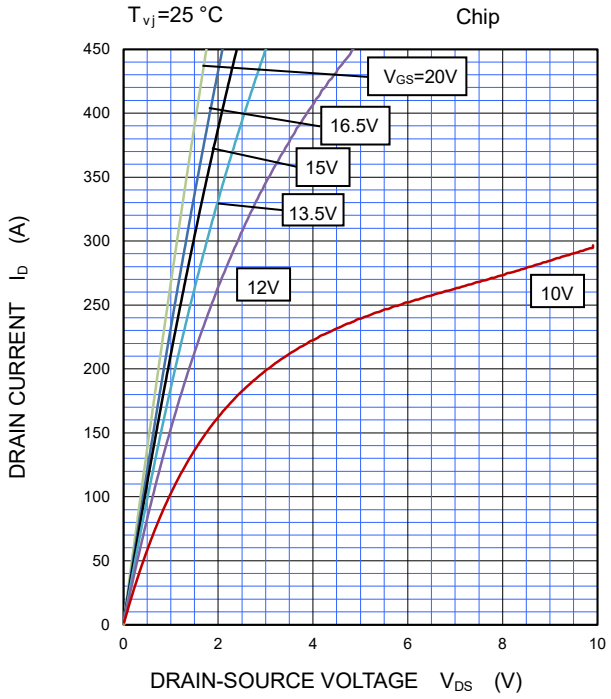


Di1

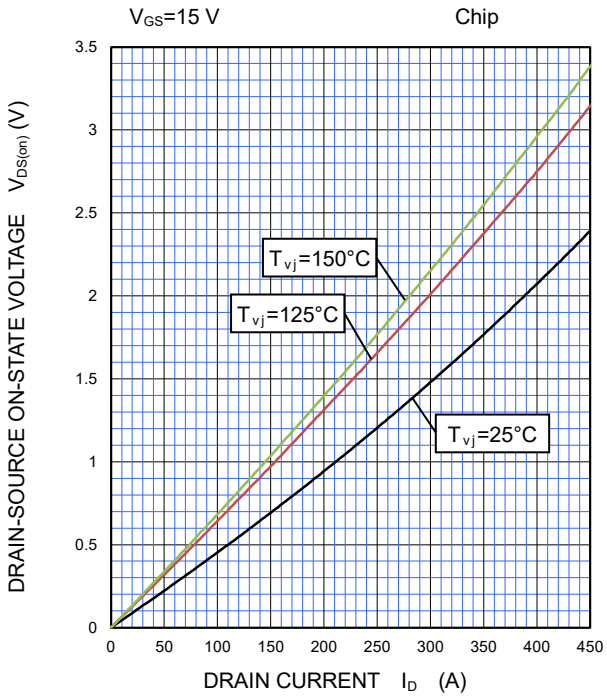
V_{SD} test circuit, V_{GS}=-15V (x: Connected a* and b*)

PERFORMANCE CURVES

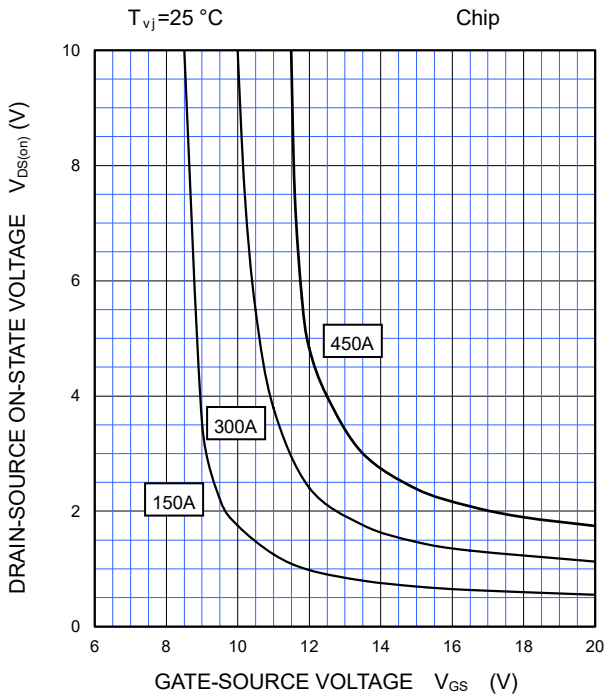
OUTPUT CHARACTERISTICS (TYPICAL)



MOSFET ON STATE VOLTAGE CHARACTERISTICS (TYPICAL)



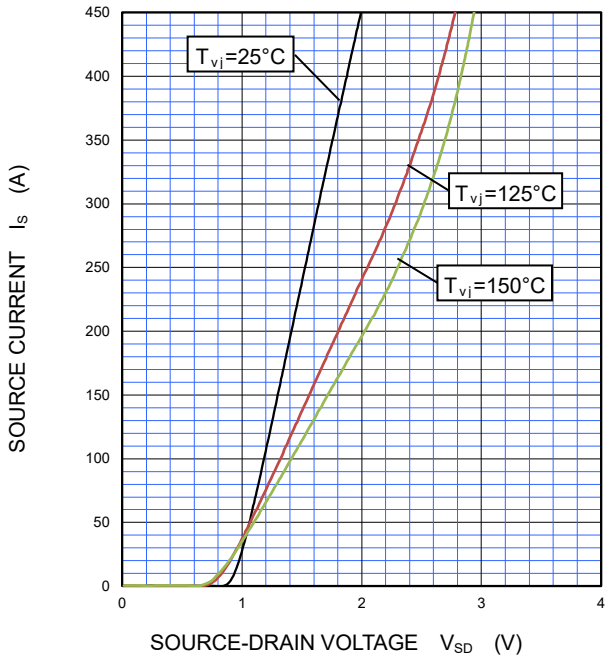
MOSFET ON STATE VOLTAGE CHARACTERISTICS (TYPICAL)



PERFORMANCE CURVES

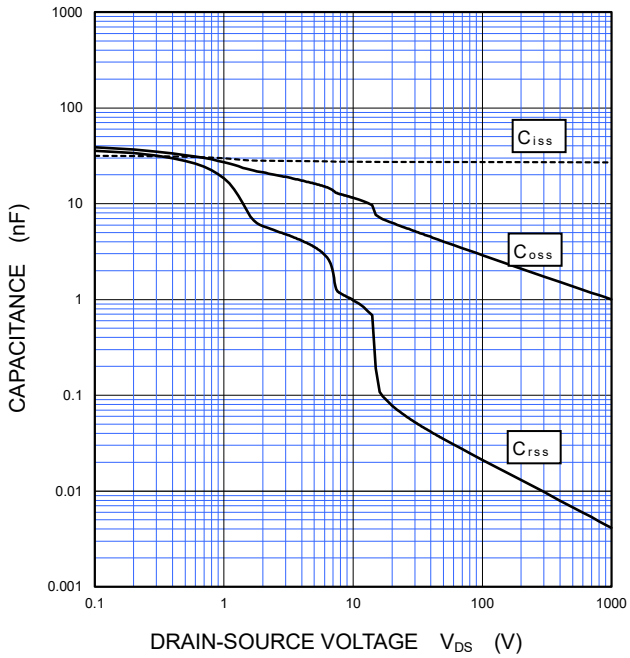
DIODE FORWARD CHARACTERISTICS (TYPICAL)

Chip



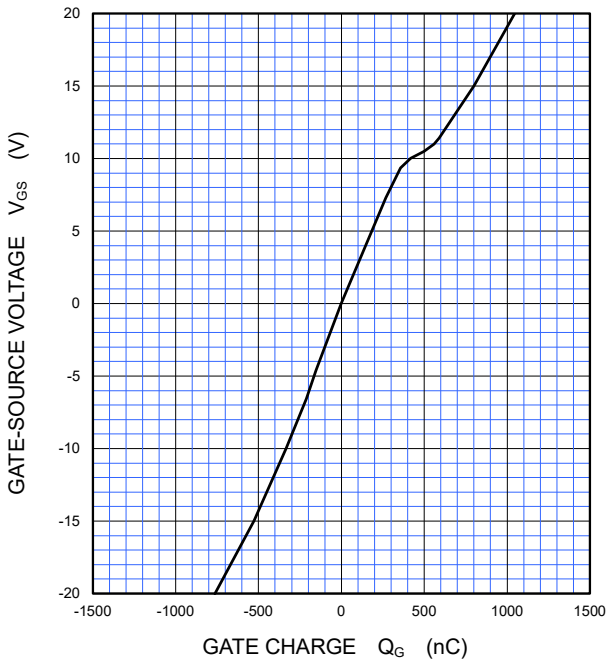
MOSFET CAPACITANCE CHARACTERISTICS (TYPICAL)

V_{GS}=0V, T_{vj}=25 °C



GATE CHARGE CHARACTERISTICS (TYPICAL)

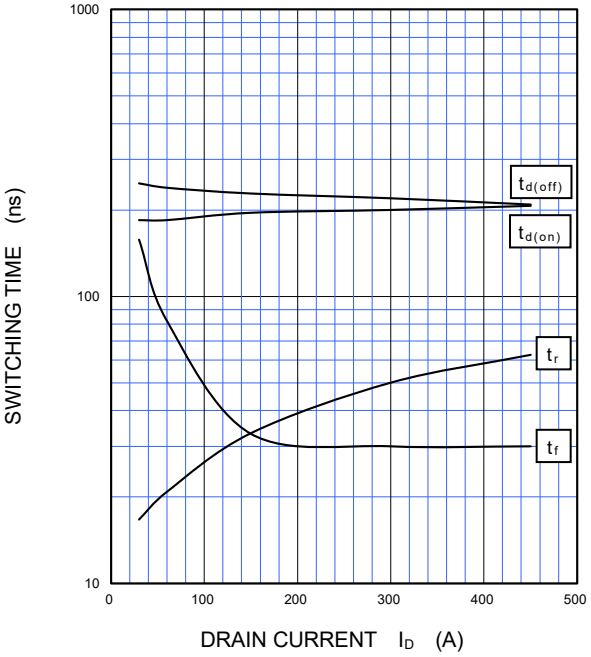
V_{DD}=900V, I_D=300 A, T_{vj}=25 °C



PERFORMANCE CURVES

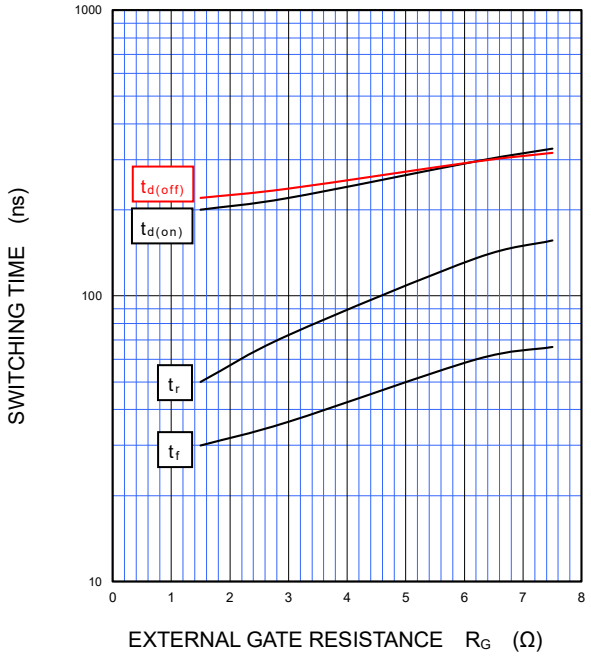
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

V_{DD}=900 V, V_{GS}=±15 V, R_G=1.5 Ω, T_{vj}=150 °C, L_{s_ext}=16nH
INDUCTIVE LOAD, PER PULSE



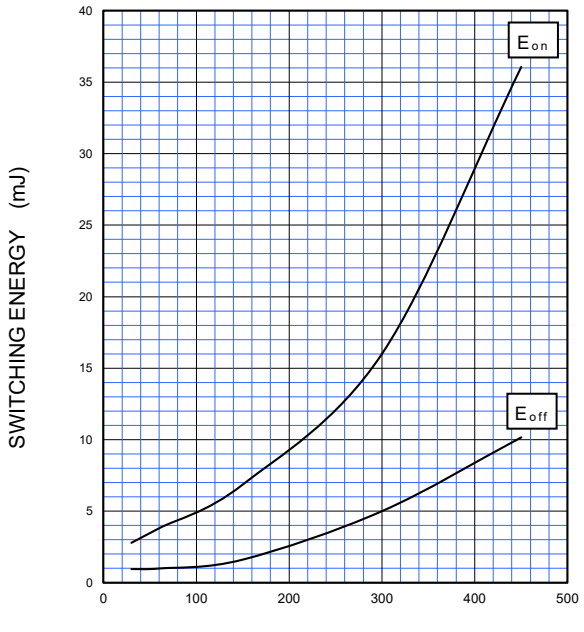
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

V_{DD}=900 V, V_{GS}=±15 V, I_D=300 A, T_{vj}=150 °C, L_{s_ext}=16nH
INDUCTIVE LOAD, PER PULSE



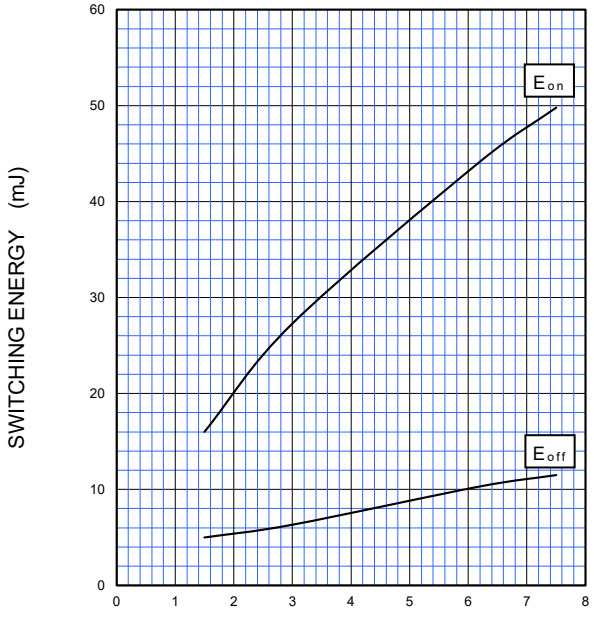
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

V_{DD}=900 V, V_{GS}=±15 V, R_G=1.5Ω, T_{vj}=150 °C, L_{s_ext}=16nH
INDUCTIVE LOAD, PER PULSE



HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

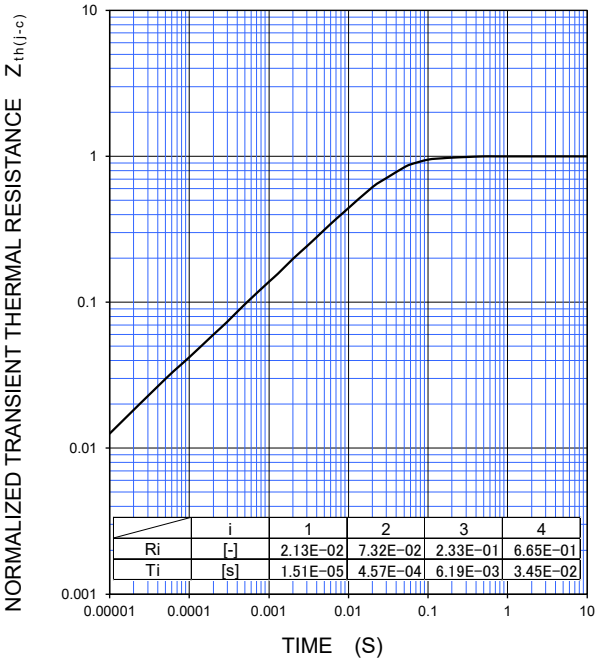
V_{DD}=900 V, V_{GS}=±15 V, I_D=300 A, T_{vj}=150 °C, L_{s_ext}=16nH
INDUCTIVE LOAD, PER PULSE



PERFORMANCE CURVES

TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)

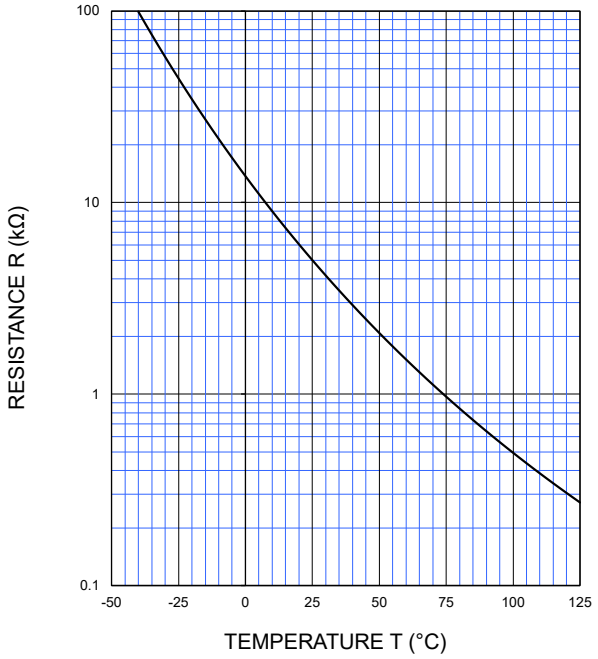
Single pulse, T_C=25 °C
$R_{th(j-c)Q}$=121K/kW, $R_{th(j-c)D}$=131K/kW



	i	1	2	3	4
Ri	[-]	2.13E−02	7.32E−02	2.33E−01	6.65E−01
Ti	[s]	1.51E−05	4.57E−04	6.19E−03	3.45E−02

NTC thermistor part

TEMPERATURE CHARACTERISTICS (TYPICAL)



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

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